

## Metal Composite Power Inductor (Thin Film) Specification Sheet



### CIGT252010EH2R2MNE (2520 / EIA 1008)

### **APPLICATION**

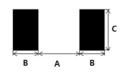
Smart phones, Tablet, Wearable devices, Power converter modules, etc.



### **FEATURES**

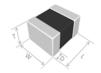
Small power inductor for mobile devices
Low DCR structure and high efficiency inductor for power circuits.
Monolithic structure for high reliability
Free of all RoHS-regulated substances
Halogen free

### RECOMMENDED LAND PATTERN



	Unit : mm
TYPE	2520
Α	1.2
В	0.8
С	2.0

### DIMENSION



TYPE	Dimension [mm]						
IIFL	L	W	Т	D			
2520	2.5±0.2	2.0±0.2	1.0 max	0.55±0.25			

### DESCRIPTION

Part no.	Size Thickness [mm] (max)	Thickness	Inductance	Inductance tolerance	DC Resist	ance [mΩ]	Rated DC Cu	rrent (Isat) [A]	Rated DC C	urrent (Irms) A]
Рап по.		[uH]	(%)	Max.	Тур.	Max.	Тур.	Max.	Тур.	
CIGT252010EH2R2MNE	1008/2520	1.0	2.2	±20	80	67	2.5	2.7	2.4	2.6

- \* Inductance : Measured with a LCR meter 4991A(Agilent) or equivalent (Test Freq. 1MHz, Level 0.1V)
- \* DC Resistance : Measured with a Resistance HI-TESTER 3541(HIOKI) or equivalent
- \* Maximum allowable DC current : Value defined when DC current flows and the initial value of inductance has decreased by 30% or

when current flows and temperature has risen to 40 ℃ whichever is smaller. (Reference: ambient temperature is 25 ℃±10)

(Isat): Allowable current in DC saturation: The DC saturation allowable current value is specified when the decrease of

the initial inductance value at 30% (Reference: ambient temperature is  $25\,^{\circ}\text{C}\pm10$ )

(Irms): Allowable current of temperature rise: The temperature rise allowable current value is specified when temperature of

the inductor is raised 40  $^{\circ}$ C by DC current. (Reference: ambient temperature is 25  $^{\circ}$ C±10)

- \* Absolute maximum voltage : Absolute maximum voltage DC 20V.
- $^{\star}$  Operating temperature range : -40 to +125°C (Including self-temperature rise)

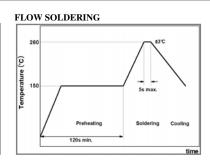
### PRODUCT IDENTIFICATION

<u>CIG</u>	<u>T</u>	<u>2520</u>	<u>10</u>	<u>EH</u>	<u>2R2</u>	M	<u>N</u>	<u>E</u>
(1)	(2)	(3)	(4)	(5)	(6)	(7)	(8)	(9)

- (1) Power Inductor
- (3) Dimensior (2520: 2.5mm × 2.0mm )
- (5) Remark (Characterization Code)
- (7) Toleranc (M:±20%)
- (8) Internal Code
- (9) Packaging (C:paper tape, E:embossed tape)
- (2) Type (T: Metal Composite Thin Film Type)
- (4) Thicknes (10: 1.0mm)
- (6) Inductan (2R2: 2.2 uH)

### RECOMMENDED SOLDERING CONDITION

# REFLOW SOLDERING 280 200 10s max. Preheating Soldering Cooling 30 - 60s time



IRON SOLDERING	
Temperature of	280 ℃ max.
Soldering Iron Tip	280 C max.
Preheating	150℃min.
Temperature	130 € 111111.
Temperature	ΔT≤130℃
Differential	$\Delta 1 \ge 130 \text{ C}$
Soldering Time	3sec max.
Wattage	50W max

### PACKAGING

Packaging Style	Quantity(pcs/reel)
Embossed Taping	3000 pcs

Item	Specified Value	1	Fest Condition		
Solderability	More than 90% of terminal electrode should be soldered newly.		for 4±1 seconds, and preheated at , the specimen shall be immersed in seconds.		
Resistance to Soldering	No mechanical damage. Remaining terminal Electrode: 75% min. Inductance change to be within ±20% to the initial.	•	for 4±1 seconds, and preheated at , the specimen shall be immersed in ±0.5 seconds.		
Thermal Shock (Temperature Cycle test)	No mechanical damage Inductance change to be within ±20% to the initial.	Repeat 100 cycles under the following conditions40±3 $^{\circ}$ C for 30 min $\rightarrow$ 85±3 $^{\circ}$ C for 30 min			
High Temp. Humidity Resistance Test	No mechanical damage Inductance change to be within ±20% to the initial	Measure the test items a	85±2°C, 85%RH, for 500±12 hours. Measure the test items after leaving at normal temperature and humidity for 24 hours.		
Low Temperature Test	No mechanical damage Inductance change to be within ±20% to the initial.	Solder the sample on PC at -55±2°C for 500±12 ho Measure the test items a and humidity for 24hours	urs. fter leaving at normal temperature		
High Temperature Test	No mechanical damage Inductance change to be within ±20% to the initial.	hours.	B. Exposure at 125±2°C for 500±12 fter leaving at normal temperature		
High Temp. Humidity Resistance Loading Test	No mechanical damage Inductance change to be within ±20% to the initial		Current for 500±12 hours. fter leaving at normal temperature s.		
High Temperature Loading Test	No mechanical damage Inductance change to be within ±20% to the initial	85±2°C, Rated Current for 500±12 hours.  Measure the test items after leaving at normal temperature and humidity for 24 hours.			
Reflow Test	No mechanical damage Inductance change to be within ±20% to the initial				
Vibration Test	No mechanical damage Inductance change to be within ±20% to the initial.  Solder the sample on PCB. Vibrate as apply 10~5 amplitude for 2 hours in each of three(X,Y,Z) axis hours).				
	No mechanical damage	Bending Limit; 2mm Test Speed; 1.0mm/sec. Keep the test board at th PCB thickness : 1.6mm	e limit point in 5 sec.		
Bending Test	19	20 R340 45	Unit :mm		
	No indication of peeling shall occur on the terminal electrode.	W(kgf)	TIME(sec)		
Terminal Adhesion Test		0.5	10±1		
Drop Test	No mechanical damage Inductance change to be within ±20% to the initial.	Random Free Fall test on concrete plate. 1 meter, 10 drops			
lpeak (AC+DC Load Life)	No mechanical damage Inductance change to be within ±20% to the initial	85±2°C, 85%RH, Load(Ipeak) for 120 hours. (Frequncy:1MHz, Load(Ipeak):1.5hr on / 0.5hr off) Measure the test items after leaving at normal temperature and humidity for 24 hours.  * Load(Ipeak) = Irms(max)×1.4			



### Metal Composite Power Inductor (Thin Film)

### RoHS+Halogen Compliant • Copparts

### **Data Sheet**

### 1. Model: CIGT252010EH2R2MNE

### 2. Description

Part no.	Size Thickness [mm] (max)		Inductance	toloranco	DC Resist	ance [mΩ]	Rated DC Cu	rrent (Isat) [A]	Rated DC C	( -,
		[uH]	(%)	Max.	Тур.	Max.	Тур.	Max.	Тур.	
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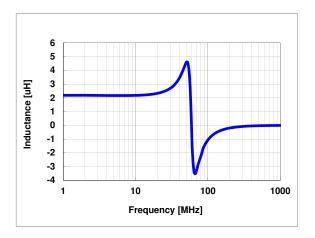
(Irms) : Allowable current of temperature rise : The temperature rise allowable current value is specified when temperature of the inductor is raised 40 ℃ by DC current. (Reference: ambient temperature is 25 ℃±10)

- \* Absolute maximum voltage : Absolute maximum voltage DC 20V.
- \* Operating temperature range: -40 to +125°C (Including self-temperature rise)

### 3. Characteristics data

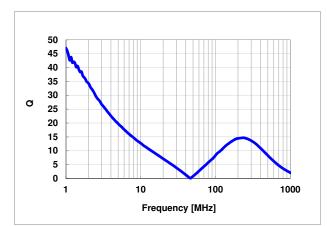
### 1) Frequency characteristics (Ls)

Agilent E4294A +E4991A , 1MHz to 1,000MHz

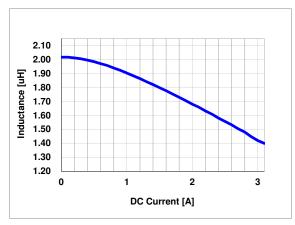


### 2) Frequency characteristics (Q)

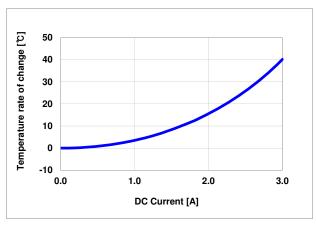
Agilent E4294A +E4991A , 1MHz to 1,000MHz



### 3) DC Bias characteristics (Typ.)



### 4)Temperature characteristics (Typ.)





Any data in this sheet are subject to change, modify or discontinue without notice The data sheets include the typical data for design reference only. If there is any question regarding the data sheets, please contact our sales personnel or application engineers